

Laboratory	Electronics Test & Development Centre, Environmental Lab, STQC Dte., DeitY, MCIT, Govt. of India, Kamala Nagar ECIL Post, Hyderabad, Telangana		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electrical Testing	Issue Date	10.09.2014
Certificate Number	T-0163	Valid Until	09.09.2016
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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
I. ENVIRONMENTAL TEST FACILITY				
1.	All Electronic/ Electrical Products	Cold test	IS 9000(Part II/Sec- 1 to 4)-1977 JSS 55555 :2000 Revision 02 IEC 60068-2-1-2007 QM 333/Issue :March 2010 MIL STD 810G Method 502.5-2008	-70°C Qualitative
		Dry Heat	IS 9000(Part III/Sec-1 to 5)-1977 JSS 55555 Test No.17-2000 Revision 2 IEC 60068-2-2 -2007 QM 333/Issue :March 2010 MIL STD 810G Method 501.5-2008	180°C Qualitative
		Damp Heat	IS 9000(Part IV) –2008 IS 9000(Part V/Sec-1 & 2)-1981 JSS 55555 Test No.10-2000 Rev. 2 IEC 60068-2-3-1969 IEC 60068-2-4-1960 IEC 60068-2-30-2005 IEC 60068-2-38-2009 QM 333/Issue : March 2010 MIL STD 202G Method 103B-2002 MIL 810G Method 507.5-2008	20° C to 90° C 20% to 98% RH Qualitative

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	All Electronic/ Electrical Products	Salt Mist Corrosion	IS 9000 (Part 11) -1983 JSS 55555 Test No.9-2000 Rev. 2 QM 333/Issue :March 2010 MIL STD 810G Method 509.5 –2000	Amb. to 55 ° C Qualitative
		Change of temperature	IS 9000 (Part –XIV)- 1988 IEC 60068-2-14-2009 QM 333/Issue :March 2010	-70 ° C to 160 ° C Qualitative
		Thermal Shock test	IS 9000(Part-XIV) –1988 IEC 60068-2-14-2009 MIL STD. 810G Method 503.5-2008 MIL STD.202G Method 107G-2002	-75 ° C to 195 ° C Qualitative
		Sinusoidal Vibration	IEC 60571-1998-02 IS 9001 (Part XIII)- 1981 IS 9000(Part-VIII)-1981 QM 333/Issue :March 2010 , JSS 55555:2000 Revision 02 IEC 60068-2-6 edition 7.0 2007	1 Ton force 5Hz to 2kHz Displacement ±20mm/20g
		Random vibration	IEC 60068-2-64 edition 2.0 2008 IEC 61373 edition 2.0 2010	1 Ton force 5Hz to 2kHz Displacement ±20 mm Acceleration : 30 g

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	All Electronic/ Electrical Products	Drop & Topple	JSS 55555-2000 Revision No. 2 IS 9000 (Part VII/ Section 3) 1979 QM 333/Issue :March 2010	Platform size : 1m x1m Height of drop as per relevant spec.
		Insulation Resistance Test	IS 616:2010 IS :302 -2008	Upto 1000V DC IR Upto 1GΩ
		High Voltage Break Down Tester	IS :302 -2008 Clause No: 16, IEC 60950 Ed 1 Clause No: 5-2005 IS 616:2010	Up to 5 kV AC

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